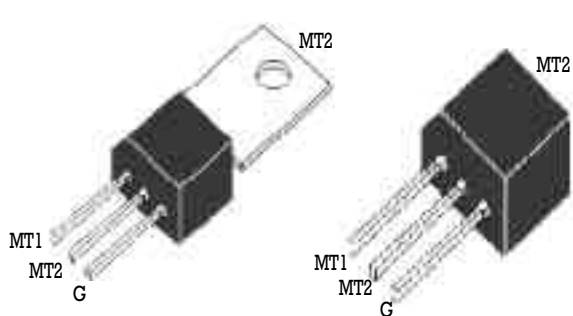


LOGIC LEVEL TRIAC

TO202-1 (E)	TO202-3 (F)	On-State Current 4 Amp	Gate Trigger Current < 5 mA to < 10 mA
		Off-State Voltage 200 V ÷ 600 V	
This series of TRIAC s uses a high performance PNPN technology.			
These parts are intended for general purpose AC switching applications with highly inductive loads.			

Absolute Maximum Ratings, according to IEC publication No. 134

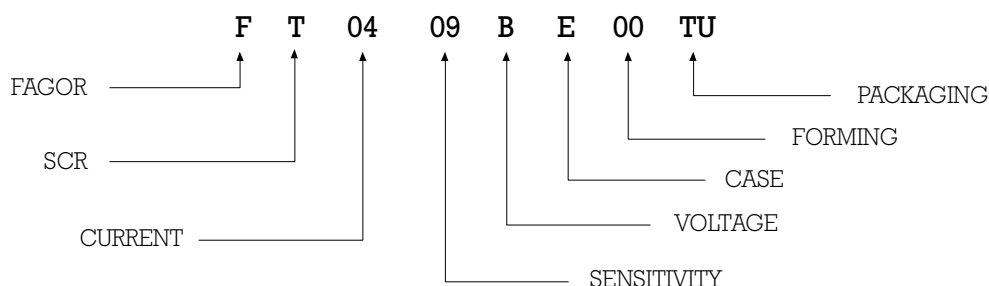
SYMBOL	PARAMETER	CONDITIONS	Min.	Max.	Unit
$I_{T(RMS)}$	RMS On-state Current	All Conduction Angle, $T_c = 110\text{ }^\circ\text{C}$	4		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 60 Hz	21		A
I_{TSM}	Non-repetitive On-State Current	Half Cycle, 50 Hz	20		A
I^2t	Fusing Current	$t_p = 10\text{ ms}$, Half Cycle	2.2		A^2s
I_{GM}	Peak Gate Current	20 μs max.		1.2	A
P_{GM}	Peak Gate Dissipation	20 μs max.		2	W
$P_{G(AV)}$	Gate Dissipation	20 ms max.		0.2	W
di/dt	Critical rate of rise of on-state current	$I_G = 2 \times I_{GT}$ Tr 200 ns, F = 120 Hz $T_j = 125\text{ }^\circ\text{C}$	20		A/ μs
T_j	Operating Temperature		-40	+125	$^\circ\text{C}$
T_{stg}	Storage Temperature		-40	+150	$^\circ\text{C}$
T_{sld}	Soldering Temperature	1.6 mm from case, 10s max.		260	$^\circ\text{C}$

SYMBOL	PARAMETER	CONDITIONS	VOLTAGE			Unit
			B	D	M	
V_{DRM} V_{RRM}	Repetitive Peak Off State Voltage	$R_{GK} = 1\text{ K}$	200	400	600	V

LOGIC LEVEL TRIAC
Electrical Characteristics

SYMBOL	PARAMETER	CONDITIONS	Quadrant		SENSITIVITY		Unit
					05	09	
I_{GT}	Gate Trigger Current	$V_D = 12 V_{DC}, R_L = 30 \Omega, T_j = 25^\circ C$	Q1÷Q3	MAX	5	10	mA
				MAX	5	10	mA
I_{DRM} / I_{RRM}	Off-State Leakage Current	$V_D = V_{DRM}, T_j = 125^\circ C$ $V_R = V_{RRM}, T_j = 25^\circ C$		MAX	0.5		mA
				MAX	5		μA
V_{to}	Threshold Voltage	$T_j = 125^\circ C$		MAX	0.95		V
R_d	Dynamic Resistance	$T_j = 125^\circ C$		MAX	180		m
V_{TM}^*	On-state Voltage	$I_T = 5.5 \text{ Amp}, t_p = 380 \mu s, T_j = 25^\circ C$		MAX	2		V
V_{GT}	Gate Trigger Voltage	$V_D = 12 V_{DC}, R_L = 30 \Omega, T_j = 25^\circ C$	Q1÷Q4	MAX	1.3		V
V_{GD}	Gate Non Trigger Voltage	$V_D = V_{DRM}, R_L = 3.3K \Omega, T_j = 125^\circ C$	Q1÷Q4	MIN	0.2		V
I_H^*	Holding Current	$I_T = 50 \text{ mA}, T_j = 25^\circ C$		MAX	7	10	mA
I_L	Latching Current	$I_G = 1.2 I_{GT}, T_j = 25^\circ C$	Q1,Q3,Q4	MAX	10	15	mA
			Q2	MAX	15	25	mA
dv / dt^*	Critical Rate of Voltage Rise	$V_D = 0.67 \times V_{DRM}, \text{ Gate open}$ $T_j = 125^\circ C$		MIN	20	100	V/ μs
$(dv/dt)_c^*$	Critical rise rate of commutating off-state Voltage	$(di/dt)_c = 1.8 \text{ A/ms}, T_j = 110^\circ C$		MIN	1	2	V/ μs
$R_{th(j-l)}$	Thermal Resistance Junction-Leads for AC				15		$^\circ C/W$
$R_{th(j-a)}$	Thermal Resistance Junction-Ambient				100		$^\circ C/W$

(*) For either polarity of electrode MT2 voltage with reference to electrode MT1.

PART NUMBER INFORMATION


LOGIC LEVEL TRIAC

Fig. 1: Maximum average power dissipation versus RMS on-state current (full cycle)

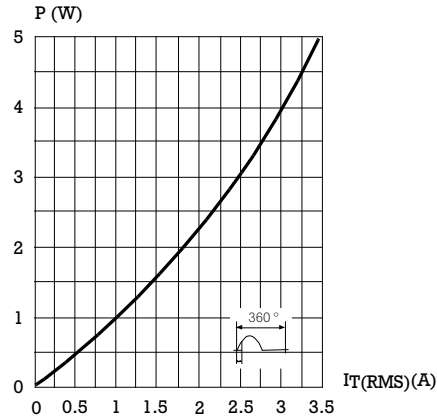


Fig. 3: Relative variation of thermal impedance junction to ambient versus pulse duration.

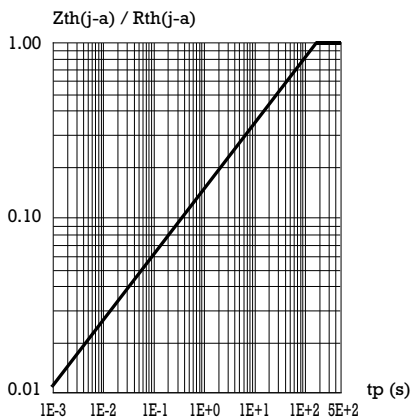


Fig. 5: Non repetitive surge peak on-state current versus number of cycles.

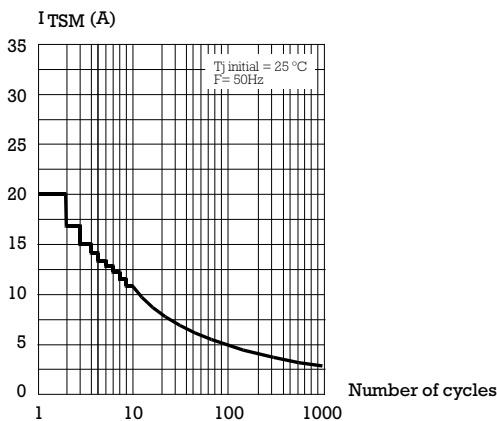


Fig. 2: RMS on-state current versus ambient temperature (full cycle)

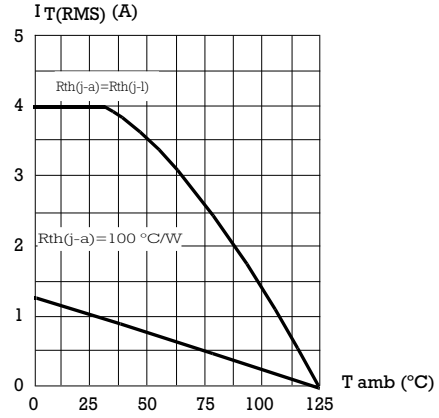


Fig. 4: Relative variation of gate trigger current, holding and latching current versus junction temperature.

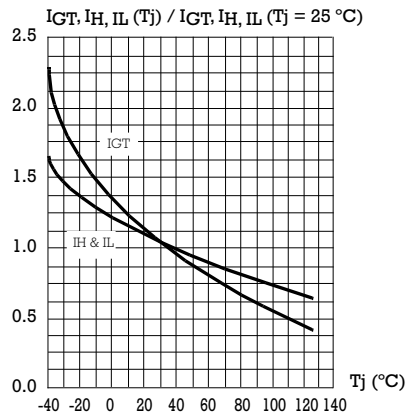
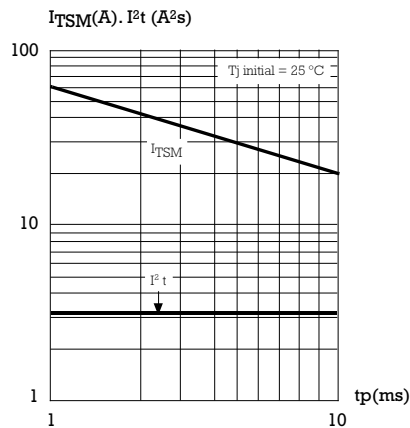
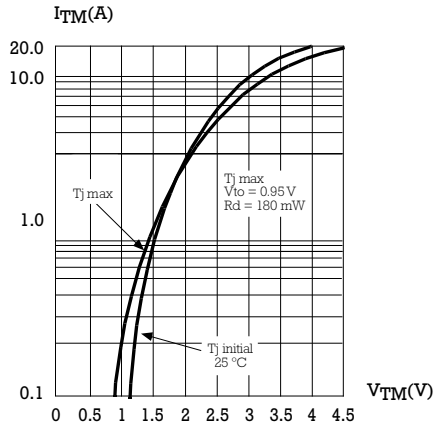


Fig. 6: Non repetitive surge peak on-state current for a sinusoidal pulse with width: t_p 10 ms, and corresponding value of I^2t .



LOGIC LEVEL TRIAC

Fig. 7: On-state characteristics (maximum values)



PACKAGE MECHANICAL DATA

TO 202-1 TO 202-3

TO 202-1

TO 202-3

